

## **AUTOMOTIVE GRADE**

**AUIRFS8407-7P** 

### **Features**

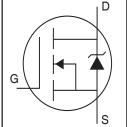
- Advanced Process Technology
- New Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

### **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.

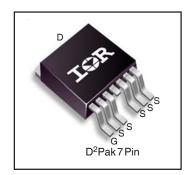
## **Applications**

- Electric Power Steering (EPS)
- Battery Switch
- Start/Stop Micro Hybrid
- Heavy Loads
- DC-DC Applications



## HEXFET® Power MOSFET

V <sub>DSS</sub>	40V
R <sub>DS(on)</sub> typ.	$1.0$ m $\Omega$
max.	$1.3$ m $\Omega$
I <sub>D (Silicon Limited)</sub>	306AO
I <sub>D (Package Limited)</sub>	240A



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form Quantity		
		Tube	50	AUIRFS8407-7P
AUIRFS8407-7P D2Pak-7PIN		Tape and Reel Left	800	AUIRFS8407-7TRL
		Tape and Reel Right	800	AUIRFS8407-7TRR

## **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	<b>306</b> ①	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) 216①		A
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited) 240		_ A
I <sub>DM</sub>	Pulsed Drain Current ②	1040	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	231	W
	Linear Derating Factor	1.5	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	٧
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy ③	344	
E <sub>AS (tested)</sub>	Single Pulse Avalanche Energy Tested Value ®	508	mJ
I <sub>AR</sub>	Avalanche Current ②	See Fig. 14, 15, 24a, 24b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ②	]	mJ
$T_J$	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/



## **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case 9 ®		0.65	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ®		40	

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.035		V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA <sup>②</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		1.0	1.3	mΩ	$V_{GS} = 10V, I_D = 100A$ §
$V_{GS(th)}$	Gate Threshold Voltage	2.2		3.9	V	$V_{DS} = V_{GS}, I_D = 150 \mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μA	$V_{DS} = 40V, V_{GS} = 0V$
				150		$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	n 1	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	l		-100	nA	$V_{GS} = -20V$
R <sub>G</sub>	Internal Gate Resistance	I	2.2		Ω	

## Dynamic @ T<sub>.I</sub> = 25°C (unless otherwise specified)

Dynamic @	1) = 25 C (unless otherwise specified)					
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	122			S	$V_{DS} = 10V, I_{D} = 100A$
$Q_g$	Total Gate Charge		150	225		$I_{D} = 100A$
$Q_{gs}$	Gate-to-Source Charge		41		nC	$V_{DS} = 20V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		51			V <sub>GS</sub> = 10V ⑤
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		99			$I_D = 100A, V_{DS} = 0V, V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-On Delay Time		18			$V_{DD} = 20V$
t <sub>r</sub>	Rise Time		62		ns	$I_D = 30A$
t <sub>d(off)</sub>	Turn-Off Delay Time		78		115	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		51			V <sub>GS</sub> = 10V ⑤
C <sub>iss</sub>	Input Capacitance		7437			$V_{GS} = 0V$
Coss	Output Capacitance		1097			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		748		pF	f = 1.0  MHz
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related)		1314			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 32V $\bigcirc$
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)		1735			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V  $

#### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			306 <sup>①</sup>		MOSFET symbol
	(Body Diode)			300⊕		showing the
I <sub>SM</sub>	Pulsed Source Current			1040		integral reverse
	(Body Diode) ②			1040		p-n junction diode.
$V_{SD}$	Diode Forward Voltage		1.0	1.3	٧	$T_J = 25$ °C, $I_S = 100$ A, $V_{GS} = 0$ V $^{\textcircled{S}}$
dv/dt	Peak Diode Recovery @		3.5		V/ns	$T_J = 175^{\circ}C$ , $I_S = 100A$ , $V_{DS} = 40V$
t <sub>rr</sub>	Reverse Recovery Time		37		ns	$T_J = 25^{\circ}C$ $V_R = 34V$ ,
			38		115	$T_J = 125^{\circ}C$ $I_F = 100A$
Q <sub>rr</sub>	Reverse Recovery Charge		34		nC	$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $\odot$
			36		nc -	$T_{J} = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		1.8		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

#### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- $\mbox{\@ifnextcolorer=1.5ex} \mbox{\@ifnextcolorer=1.5ex} Limited by $T_{Jmax}$, starting $T_J=25^{\circ}$C, $L=0.069$mH, $R_G=50\Omega$, $I_{AS}=100A$, $V_{GS}=10V$. Part not recommended for use above this value.$
- ⊕ I<sub>SD</sub> ≤ 100A, di/dt ≤ 1288A/µs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 175°C.

- $\$  Pulse width  $\le 400 \mu s$ ; duty cycle  $\le 2\%$ .
- $\mbox{\ @}$   $C_{oss}$  eff. (TR) is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}.$
- $\ \ \, \ \ \,$  C  $_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as C  $_{oss}$  while V  $_{DS}$  is rising from 0 to 80% V  $_{DSS}.$
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- $\ {\rm \rlap{1}\hskip -1.5pt 0} \ R_{\theta JC}$  value shown is at time zero.



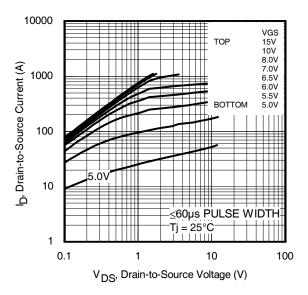


Fig 1. Typical Output Characteristics

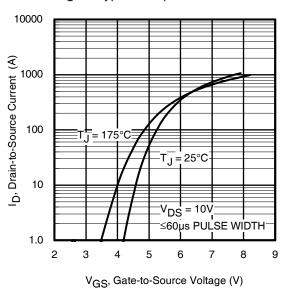


Fig 3. Typical Transfer Characteristics

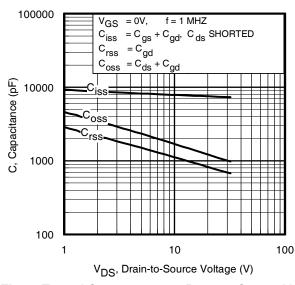


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

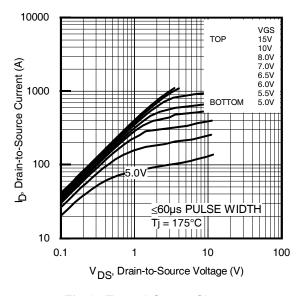


Fig 2. Typical Output Characteristics

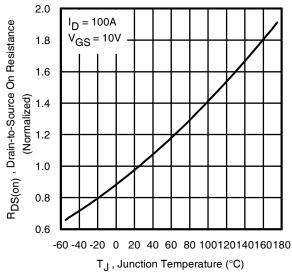


Fig 4. Normalized On-Resistance vs. Temperature

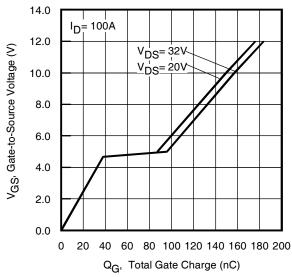
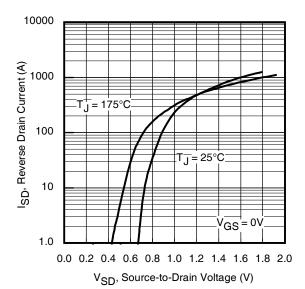
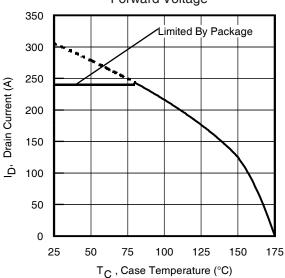


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

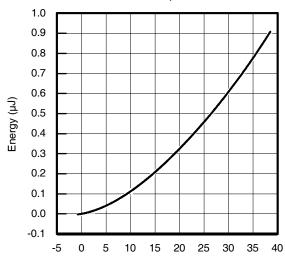




**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Case Temperature



 $\label{eq:VDS} V_{DS,} \mbox{ Drain-to-Source Voltage (V)}$  Fig 11. Typical  $C_{OSS}$  Stored Energy

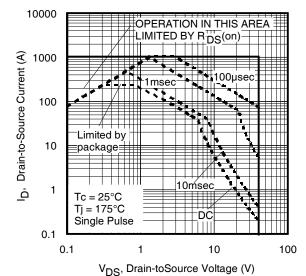


Fig 8. Maximum Safe Operating Area

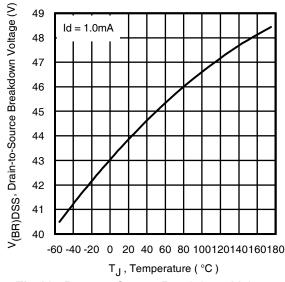


Fig 10. Drain-to-Source Breakdown Voltage

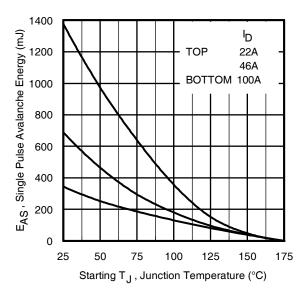


Fig 12. Maximum Avalanche Energy vs. DrainCurrent



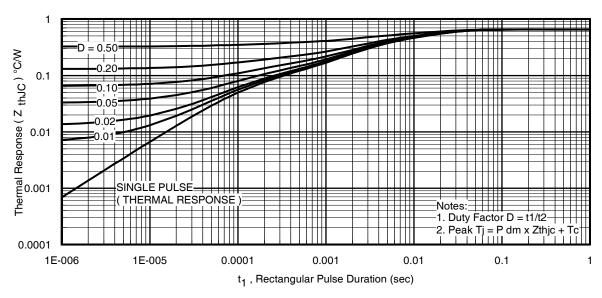


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

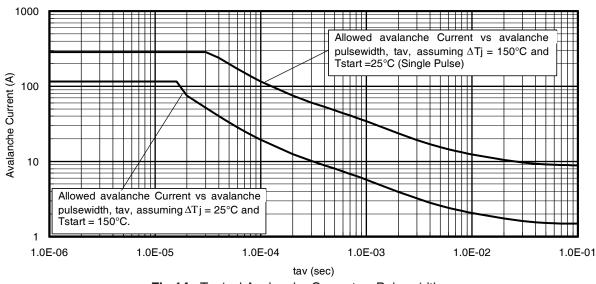


Fig 14. Typical Avalanche Current vs. Pulsewidth

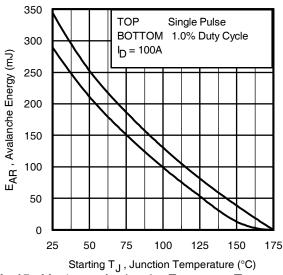


Fig 15. Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves , Figures 14, 15 (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
  - Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{\rm jmax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 24a, 24b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).
  - $t_{av}$  = Average time in avalanche.
  - D = Duty cycle in avalanche =  $t_{av} \cdot f$
  - $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; ( \; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



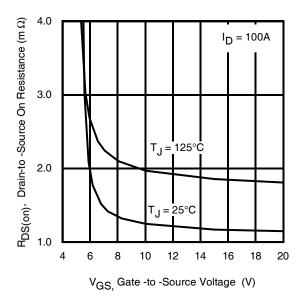


Fig 16. On-Resistance vs. Gate Voltage

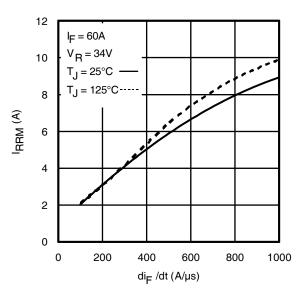


Fig. 18 - Typical Recovery Current vs. di<sub>f</sub>/dt

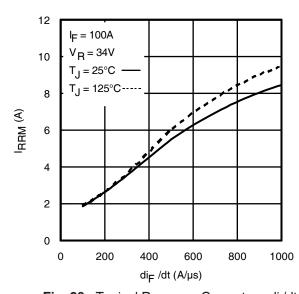


Fig. 20 - Typical Recovery Current vs. di<sub>f</sub>/dt

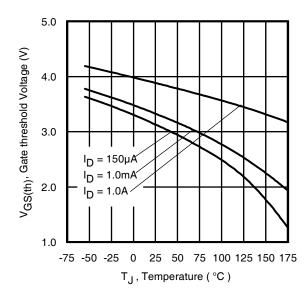


Fig 17. Threshold Voltage vs. Temperature

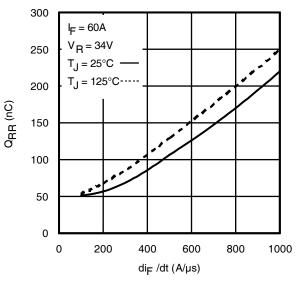


Fig. 19 - Typical Stored Charge vs. dif/dt

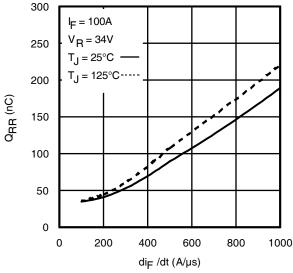


Fig. 21 - Typical Stored Charge vs. dif/dt



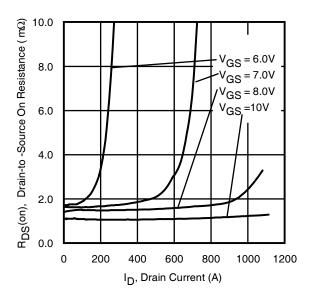


Fig 22. Typical On-Resistance vs. Drain Current



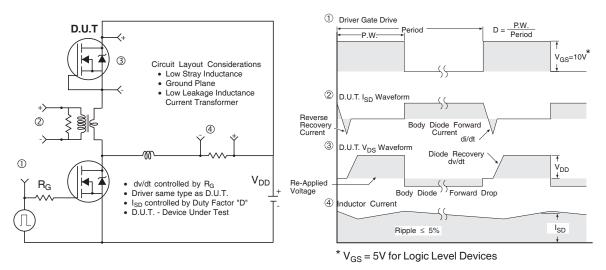


Fig 23. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

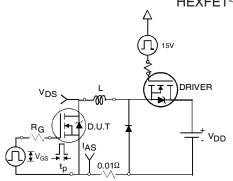


Fig 24a. Unclamped Inductive Test

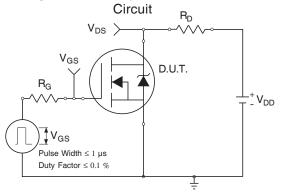


Fig 25a. Switching Time Test Circuit

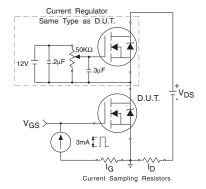


Fig 26a. Gate Charge Test Circuit

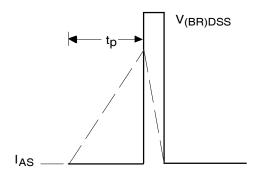


Fig 24b. Unclamped Inductive Waveforms

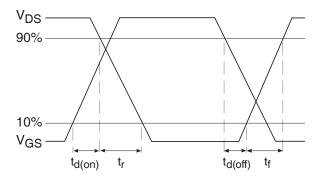


Fig 25b. Switching Time Waveforms

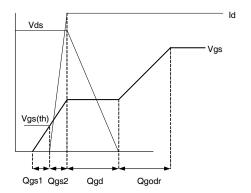
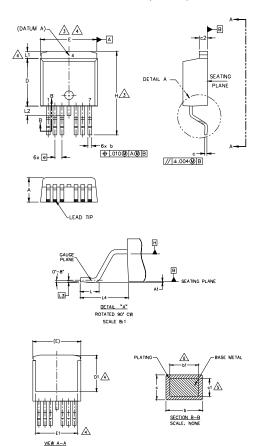


Fig 26b. Gate Charge Waveform



## D<sup>2</sup>Pak - 7 Pin Package Outline

Dimensions are shown in millimeters (inches)

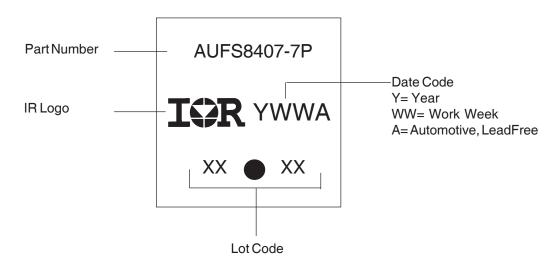


S Y M B		N				
B	MILLIM	ETERS	INC	INCHES		
L	MIN.	MAX.	MIN.	MAX.	N O T E S	
Α	4.06	4.83	.160	.190		
A1	-	0.254	-	.010		
b	0.51	0.99	.020	.036		
ь1	0.51	0.89	.020	.032	5	
С	0.38	0.74	.015	.029		
с1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9,65	.330	.380	3	
D1	6.86	-	.270		4	
Ε	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245		4	
е	1,27	BSC	.050	BSC		
Н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	-	1.68	-	.066	4	
L2	-	1.78	-	.070		
L3	0.25	BSC	.010	BSC		
L4	4.78	5.28	.188	.208		

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB.

## D<sup>2</sup>Pak - 7 Pin Part Marking Information



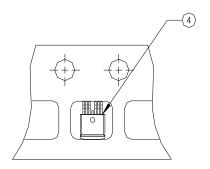
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



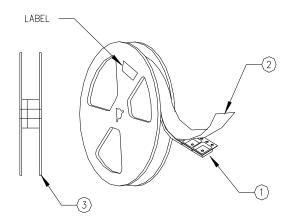
# D<sup>2</sup>Pak - 7 Pin Tape and Reel

NOTES, TAPE & REEL, LABELLING:

- 1. TAPE AND REEL.
  - 1.1 REEL SIZE 13 INCH DIAMETER.
  - 1.2 EACH REEL CONTAINING 800 DEVICES.
  - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
  - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
  - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
  - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS.
    REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS.
    HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
  - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
  - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
  - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
  - 2.4 QUANTITY:
  - 2.5 VENDOR CODE: IR
  - 2.6 LOT CODE:
  - 2.7 DATE CODE:





# Qualification Information<sup>†</sup>

		Automotive				
		(per AEC-Q101)				
Qualification	Level	Comments: This part number(s) passed Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
		D <sup>2</sup> PAK 7 Pin MSL1				
	Machine Model  Human Body Model		Class M3 (+/- 400V) <sup>††</sup> AEC-Q101-002			
ESD			Class H2 (+/- 4000V) <sup>††</sup> AEC-Q101-001			
	Charged Device Model	Class C5 (+/- 2000V) <sup>††</sup> AEC-Q101-005				
RoHS Comp	liant	Yes				

<sup>†</sup> Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

<sup>††</sup> Highest passing voltage.



### **IMPORTANT NOTICE**

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